捷多邦,专业PCB**SN54ALS564B**章**SN7**4ALS564B OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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- 3-State Buffer-Type Inverting Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- Buffered Control Inputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), Standard Plastic (N) and Ceramic (J) 300-mil DIPs, and Ceramic Flat (W) Packages

description

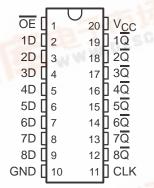
These octal D-type edge-triggered flip-flops feature inverting 3-state outputs designed specifically for bus driving. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight flip-flops enter data on the low-to-high transition of the clock (CLK) input.

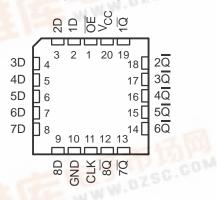
The output-enable (OE) input does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS564B is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ALS564B is characterized for operation from 0°C to 70°C.

SN54ALS564B...J OR W PACKAGE SN74ALS564B...DW OR N PACKAGE (TOP VIEW)



SN54ALS564B . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each flip-flop)

0.00	INPUTS	OU <u>T</u> PUT					
OE	CLK	D	Q				
L	1	Н	L				
L	\uparrow	L	Н				
L	L	Χ	\overline{Q}_0				
Н	Χ	Χ	Z				

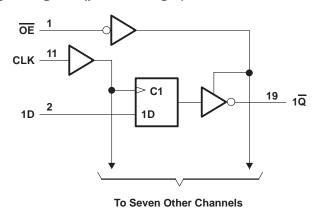
SN54ALS564B, SN74ALS564B OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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logic symbol†

OE ΕN > C1 **CLK** 2 19 1D \triangleright 1Q 1D ∇ 3 18 2D 2Q 4 17 3D 3Q 16 4Q 4D 6 15 5Q 5D 14 7 6D 6Q 8 13 7Q 7D 9 12 8D 8Q

logic diagram (positive logic)



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T _A : SN54ALS564B	−55°C to 125°C
SN74ALS564B	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS564B		SN74ALS564B			UNIT	
			NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
loL	Low-level output current			12			24	mA
fclock	Clock frequency	0		22	0		30	MHz
t _W	Pulse duration, CLK high or low	25			14			ns
t _{su}	Setup time, data before CLK↑	15			15			ns
th	Hold time, data after CLK↑	4		·	0			ns
TA	Operating free-air temperature	-55		125	0		70	°C



SN54ALS564B, SN74ALS564B OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN	SN54ALS564B			SN74ALS564B			
			MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT	
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V	
	V _{CC} = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2			
Voн	V 45 V	I _{OH} = -1 mA	2.4	3.3					V	
	V _{CC} = 4.5 V	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2			
V	V 45V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V	
VOL	V _{CC} = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V	
lozh	$V_{CC} = 5.5 V,$	V _O = 2.7 V			20			20	μΑ	
lozL	$V_{CC} = 5.5 V,$	V _O = 0.4 V			-20			-20	μΑ	
lį	$V_{CC} = 5.5 V,$	V _I = 7 V			0.1			0.1	mA	
lін	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ	
I _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.2			-0.2	mA	
1 ₀ ‡	$V_{CC} = 5.5 \text{ V},$	V _O = 2.25 V	-20		-112	-30		-112	mA	
	V _{CC} = 5.5 V	Outputs high		10	18		10	18		
Icc		Outputs low		15	24		15	24	mA	
		Outputs disabled		16	30		16	30		

 $[\]uparrow$ All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54ALS564B		SN74ALS564B		
			MIN	MAX	MIN	MAX	
f _{max}			22		30		MHz
t _{PLH}	CLK	Any Q	4	24	3	14	ns
t _{PHL}			4	20	4	14	115
^t PZH	ŌĒ	Any Q	4	24	3	18	ns
tPZL			3	23	4	18	115
^t PHZ	ŌĒ	Any Q	2	14	1	10	ns
^t PLZ			3	29	2	15	115

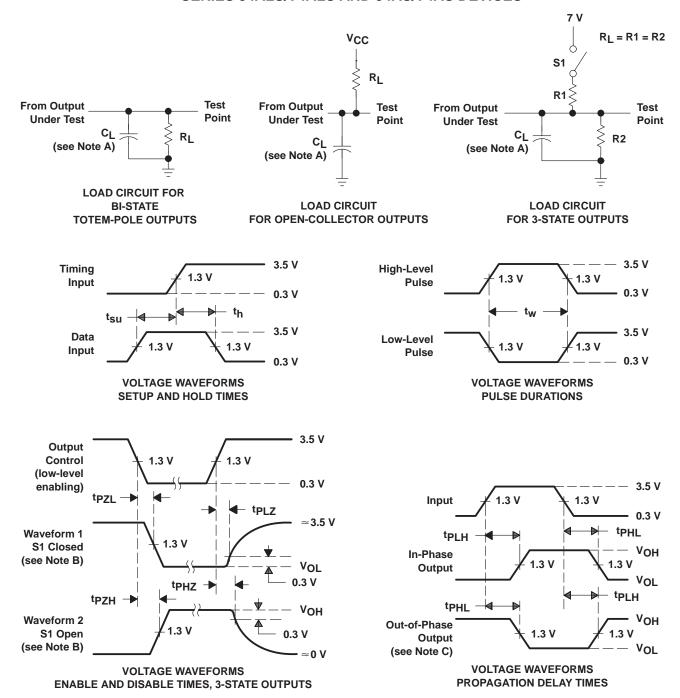
[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, los.

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PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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